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## PATENT APPLICATION

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Ichirou ISHIMARII et al.

Application No.: New U.S. Patent Application

Filed: August 17, 2006 Docket No.: 128047

For: THREE-DIMENSIONAL GEOMETRIC MEASUREMENT AND ANALYSIS SYSTEM

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- 2. Relevance of one or more non-English language reference is discussed in the present specification. See References 2.
- 3. One or more reference cited herein was cited in the International Search Report. A copy of the International Search Report is attached for the Examiner's information. See References 2 and 3.
- 4. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- 5. An English language Abstract of one or more non-English language reference is attached hereto. See References 2 and 3.
- 6. A computer-generated English language translation of one or more Japanese Patent Publication cited herein has been obtained from the website of the Japanese Patent Office ([http://www.jpo.go.jp]), and is attached, but has not been reviewed for accuracy. See References 2.

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7. Reference 1 corresponds to reference 3.

Respectfully submitted,

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JAO:DAT/jtp

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Date: August 17, 2006

OLIFF & BERRIDGE, PLC P.O. Box 19928 Alexandria, Virginia 22320 Telephone: (703) 836-6400 DEPOSIT ACCOUNT USE AUTHORIZATION Please grant any extension necessary for entry; Charge any fee due to our Deposit Account No. 15-0461 EFS-Web Receipt date: 08/17/2006

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(Use several sheets if necessary)					APPLICANTS Ichirou ISHIMARU et al.				
					FILING DATE August 17, 2006				
		U.S	S. PATEN	T DOCUM	IENTS				
Examiner Initials	Cite No.	Document Number	Da	ate	Ni	ame			
	1	2003/0048532 A1	3/13/2003		LINDNER et al.				
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	2	JP A 2002-243420			Japan		х	х	
	3	WO 02/14845 A1			WIPO		х		
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